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What is Claimed Is:

1. A method of synthesizing a register transfer level (RTL) based design of a system comprising the steps of:

determining sub-module of a top level system;

5 determining individual time budgets for each sub-module based on timing requirements of the top-level system

synthesizing gate-level designs of the sub-module based on the determined time budgets for the individual sub-modules;

10 integrating the gate-level designs of the individual sub-modules to form a top level design;

testing the top-level design for conformance with top-level design requirements; and

generating a top-level netlist when the top-level design conforms to the top-level design requirements.

2. The method of claim 1, further comprising generating gate-level netlists for the gate-level designs of each of the sub-modules.

3. The method of claim 2, wherein the step of integrating the gate-level designs includes integrating the gate-level netlists of the sub-modules.

4. The method of claim 3, further comprising testing the gate-level designs for conformance with gate-level design requirements of the individual sub-modules prior to integrating the gate-level designs to form the top-level design.

5. The method of claim 4, wherein testing the gate-level designs include performing static timing analysis on the individual sub-modules for conformance with timing requirements for the individual sub-blocks.

6. The method of claim 5, wherein the gate-level netlists are generated for the sub-modules only if the timing requirements for the individual sub-modules are met.

7. The method of claim 6, wherein the step of synthesizing is re-performed and the gate-level designs are re-tested in an iterative manner for verifying conformance of the gate-level designs with the timing requirements of the individual sub-modules.

8. The method of claim 7, wherein the step of synthesizing gate-level designs is further based on wire loads and input/output loads/drivers.

9. The method of claim 8, wherein the step of verifying conformance of the gate-level designs includes performing dynamic simulations on the gate-level designs.

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